



## Short Course Announcement Microwave Measurements for High Performance Devices and Applications



November 29-30, 2005  
Washington, D.C.

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Do you need to commit this year's educational expenses soon? Are you an engineer, technician, or scientist concerned with accurate measurement of RF and microwave quantities? If so, it might be worth planning ahead. The Automatic Radio Frequency Techniques Group (ARFTG) in cooperation with the National Institute of Standards and Technology (NIST) will offer its 2005 Microwave Measurements Short Course in Washington, D.C., on November 29 through noon, November 30. This course is held in conjunction with the 66th ARFTG Microwave Measurements Conference on December 1-2. The conference theme is, "Measurements of High Performance Devices and Applications."

The 1 ½-day course covers microwave measurement fundamentals, including vector network analysis, scattering parameters, power, and thermal noise. Practical issues such as cables, fixtures, probes, and on-wafer measurements are covered. More advanced measurement topics are also covered including microwave measurements for optoelectronic applications, scattering-parameter uncertainty analysis, electromagnetic compatibility, and an overview of wireless test instrumentation and nonlinear measurements.

This course provides an excellent introduction for newcomers to the field or a good review for those familiar with RF and microwave measurements. The course registration fee is \$400 and includes lunch on both days. Lecture notes will be provided. Class size is limited. For more information on the conference and short course see [www.arftg.org](http://www.arftg.org) or contact

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